

**Search Notes**

Application/Control No.

10/523,776

Examiner

Tianjie Chen

Applicant(s)/Patent under  
Reexamination

OSHIMA ET AL.

Art Unit

2627

**SEARCHED**

Class	Subclass	Date	Examiner
Updated		2/22/2007	TJ

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR